

# Production of CMS GEM detectors for the GE2/1 and ME0 stations

With lessons learnt from GE1/1

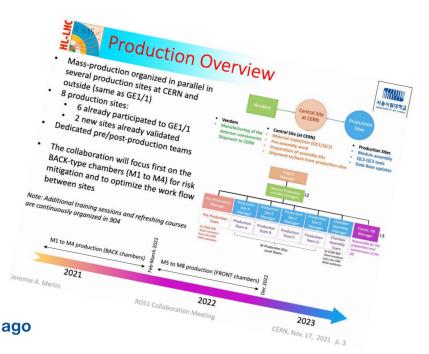
Antonello Pellecchia<sup>1</sup> for the CMS GEM group <sup>1</sup> INFN Bari

RD51 collaboration meeting - Dec 4-8 2023

### **Last update on CMS production...**







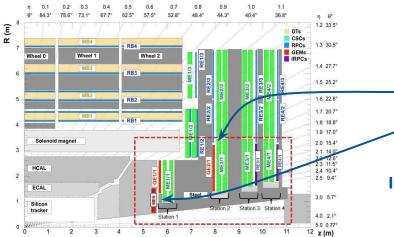
#### ... more than 2 years ago

#### Meanwhile:

- Production has continued
- First validation results are available
- Priorities have shifted
- New lessons learnt, still more to understand

Jeremie A. Merlin

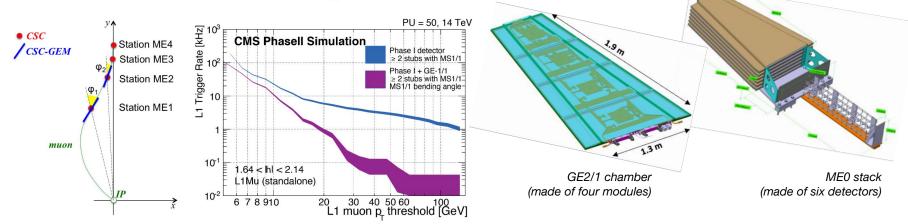
### **CINFN CMS GEM project**



- GE1/1: Complementing CSC system in 1.6 < |η| < 2.15</li>
   Early Phase-2 upgrade: already installed in 2019-2020, commissioned and taking data during Run 3
  - **GE2/1:** Complementing CSC system in  $1.6 < |\eta| < 2.4$
- **ME0:** Complementing other GEMs and CSCs in 1.6 <  $|\eta|$  < 2.4,

extending muon system coverage to  $2.4 < |\eta| < 2.8$ 

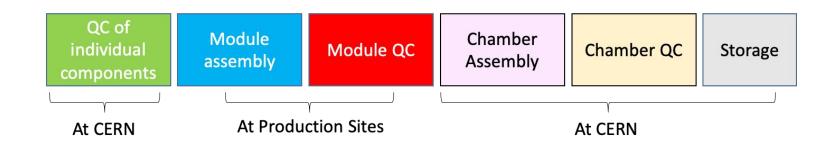
#### In this presentation: GE2/1 production status and outlook on ME0

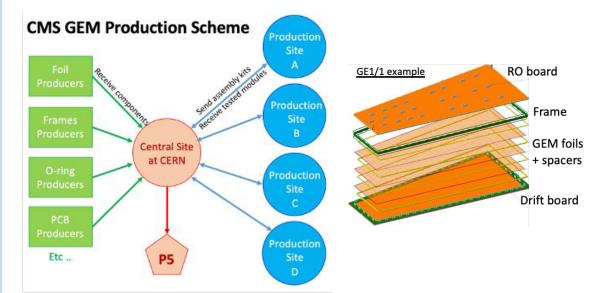


5th 2023

Dec

### **INFN** Production overview



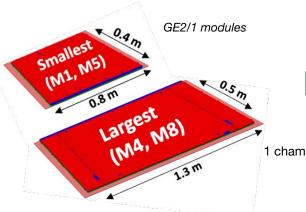


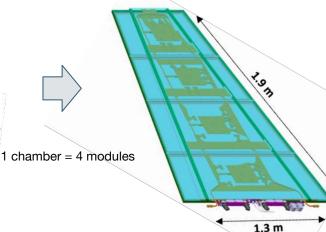
#### Production scheme as for GE1/1:

- Component QC at CERN
- Five production sites (Bari, CERN, Ghent+Aachen, Frascati, PKU) for individual modules
- Electronics, chamber assembly (4 modules together) and final validation with cosmics at CERN

## What do the detectors look like? And how have they changed?

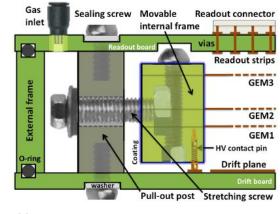
## **GE2/1** detector design





- 2 GE2/1 endcaps
- 18 "super-chambers" per endcap
- 2 chambers per "super-chamber"
   "Front" and "back" type
- 4 modules per chamber

Front modules (M5, M6, M7, M8) Back modules (M1, M2, M3, M4)



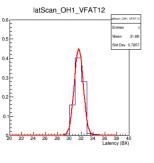
Detector and electronics design **inherited from GE1/1**, but with **lessons learnt**:

- Noise
- Protection for readout electronics
- Planarity and response uniformity
- Intrinsic time resolution



RO strips

VFAT3



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### **Lesson:** detector planarity

Problem: in GE1/1, drift and R/O PCBs tended to bend under stretching force

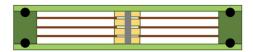
 $\rightarrow$  **dishomogeneity** of gain, efficiency and timing

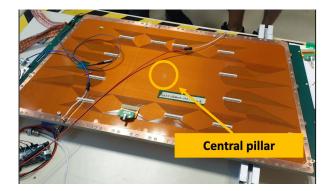
1st GE2/1 solution: pillars (sensitive to deformation on drift)



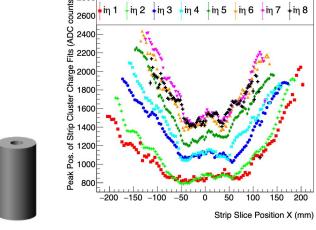
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#### 2nd GE2/1 solution: rings



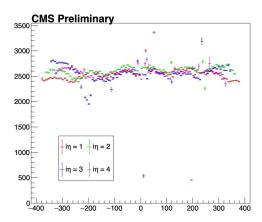


- Much improved gain uniformity and efficiency uniformity
- Reduced risk of sparks by weak spots in induction gap



Top: GE1/1 "long" detector Bottom: GE2/1 M4 module

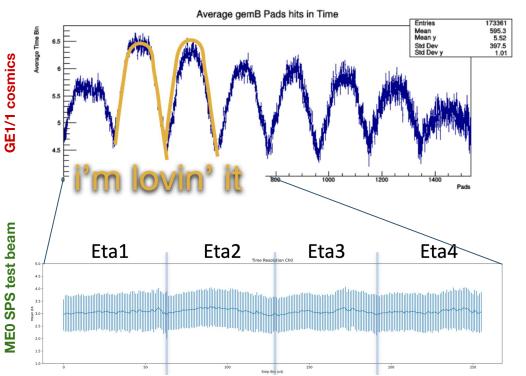
100 150



J. Merlin, GE2/1 production, in November 2021 RD51 collaboration meeting

#### **Lesson:** time resolution and planarity

The **PCB bending** was impacting the **time response uniformity** of the detector.



In GE1/1, this caused **non-uniformity in signal** rise time  $\rightarrow$  timing modulation with strip position ("basin effect")

 Fixable in GE1/1 by applying different delays to trigger primitives in GEM front-end FPGA

**Fixed in GE2/1 and ME0** design by using pillars to ensure uniformity of induction gap:

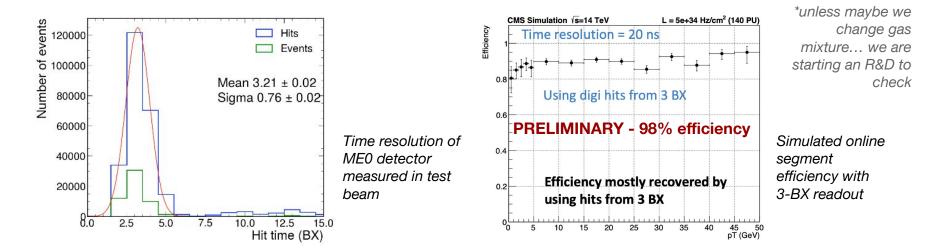
 SPS test beam results: good timing uniformity over 4 eta partitions

**Not a problem in ME0** (Should also be ok in GE2/1)

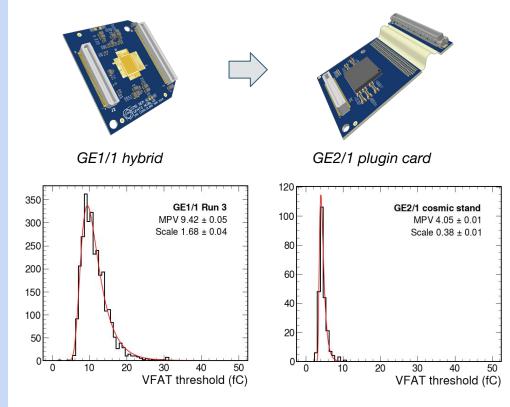
### **Surprise: time resolution and electronics**

Our time resolution with front-end electronics is 15 - 19 ns, not 8 - 10 ns

- Common issue between GE1/1, GE2/1 and ME0: analog front-end not optimized for GEM signal shape and duration
- We cannot improve the time resolution\*, but we can mitigate effect on online physics performance:
  - Reading out multiple BXs readout in back-end firmware Implemented in emulator, under development in GEM firmware
  - From first simulations, online segment efficiency recovered with matching window 3 BX Slight worsening in bending angle resolution only at "hypothetical" pile-up 300



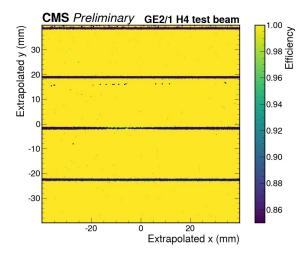
#### **INFN** Lesson: noise



Very **good S/N ratio** verified with high-granularity efficiency measurement in test beam  $\rightarrow$ 

#### Same front-end ASIC (VFAT3), new PCB

- Chip is now **packaged**, bump-bonded (higher yield compared to hybrids)
- Flex PCB for easier alignment between readout board (ROB) and GEM electronics board (GEB)
- **HRS 140** connector to R/O strips provides more grounding pins  $\rightarrow \sim x^2$  lower noise



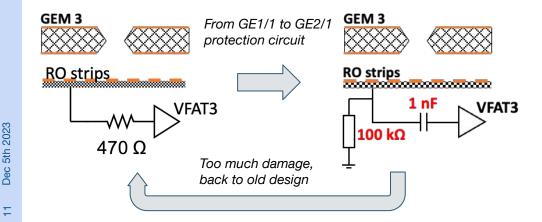
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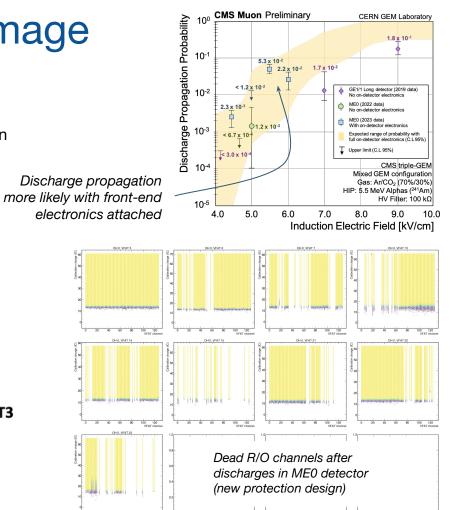
### Lesson: readout damage

GE2/1 plugin card included new "decoupling" circuit to prevent discharge propagation to front-end

- Operations with GE2/1 and ME0 detectors (demonstrator in CMS, test beam, lab measurements) showed too high probability of discharge damage
- We changed the protection circuit back to the GE1/1 design (470  $\Omega$  series resistor)

Discharge studies now show no damage (expected damage probability per chip  $< 3 \times 10^{-3}$ )







### How is the production going?

### **GEM** production schedule

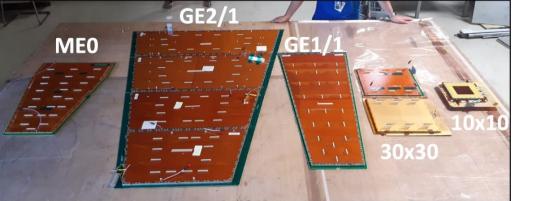


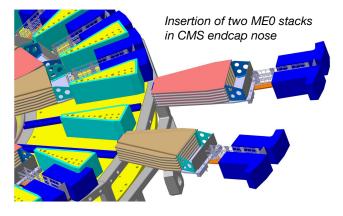
Production schedule **approved by CMS** in GE2/1 manufacturing progress review (MPR), May 2023:

- Install 30 chambers out of 36 (almost one endcap) in year-end technical stop (YETS) 2023-2024
- **Complete** production by **October 2024** (no float)
- Start **ME0** production in **November 2024**
- Complete full GE2/1 system installation in YETS 24-25

In short: complete mass production of GE2/1 before ME0

Note: ME0 installation is constrained to January 2027 by HGCAL schedule





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#### **GEM foil production**

#### Original plan: two GE2/1 foil producers

- MPT workshop (CERN): M1, M4, M5, M8
- KCMS/Mecaro (Korea): M2, M3, M6, M7

Mecaro produced **300 foils with 99% yield** Each foil delivered with in-depth QC results

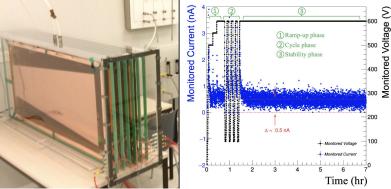
- $\rightarrow$  In 2022, Mecaro **sold** its chemical lab away
- → Production **stopped** in August 2022
- → Equipment and expertise to be relocated to KCMS
- → GE2/1 foil production not continuing at KCMS: will start again for ME0 foils

#### New plan: remaining foil production to complete at MPT workshop

- Restarted in July 2023
- Expected end in April 2024

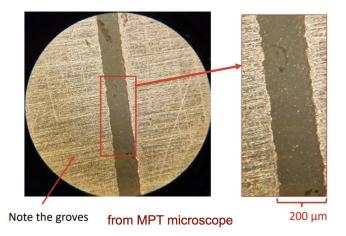
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	002A_PIStdev
CMS GEM GE21 Foils	- RO Side
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1st Delivery Celebration	002A_CUMean
	002A_CUStdev
	002A_PIMean
	997A PIStdev

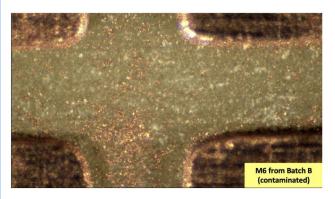
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5) Hole Diad - Drift Side Feil Inccion 8023.Cl/Ban 80	1 77.8 10.2 1.18 1 1.18	2         7835           9.85         9.85           2         7835           9.85         9.85	3 80.99 0.54 59.37 0.69 3 75.71 0.89	4 79.33 0.82 54.94 1.01 4 71.01 1.02	5 78.35 0.62 56 0.75 5 76.18 1.19	Total Avg. 74.88 1.76 52.88 1.7 Total Avg. 75.05 2.41			



### **EXAMPLE PCB** production issue

- At end of summer 2023, **98 modules** assembled (24 chambers) 36 needed for 1 endcap
- In summer, assembly team had **issues with 80%** of production modules
  - Many cleaning iterations needed during assembly
  - Shorts forming while closing detectors
- Could not see issues in drift and R/O PCBs with microscope in QC lab
- However, MPT workshop lab showed copper dust (few µm) in PCBs Cannot be removed by mechanical cleaning





Investigation on PCB quality (September 2023):

 Dust came from sanding done by PCB manufacturer (Micropack) on last PCB batch

Issue only for GE2/1

• Copper **passivation was not applied** in all PCBs: No protection against copper **oxidation** 

Affects both GE1/1 and GE2/1; impact on performance yet unknown

• We decided to refurbish all GE2/1 modules and redefine PCB validation

5th 2023

Dec

#### **INFN PCB refurbishment**

Refurbishment procedure established with the help of the **MPT Workshop**:

- Mechanical cleaning with tissue soaked with pure ethanol or isopropyl **alcohol**
- Water jet cleaning
- Micro-etching
- Chromic-acid passivation

Procedure also **applied successfully** by Micropack. No visible difference now between MPT and Micropack refurbished PCBs

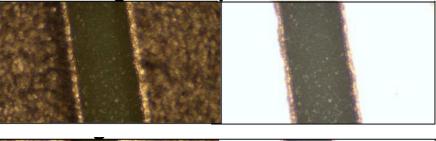
#### A validation procedure is now required for all new PCBs:

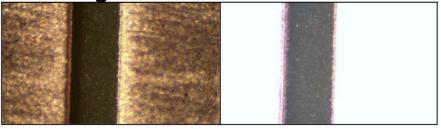
- Visual inspection
- Microscope inspection (new)

Inspection on several points on the PCBs with different light intensity

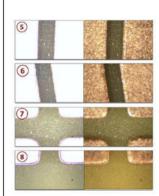
• Strip continuity/shorts (updated)

#### Still investigating on how to fix contaminated GEM foils









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### **INFN** New production plan

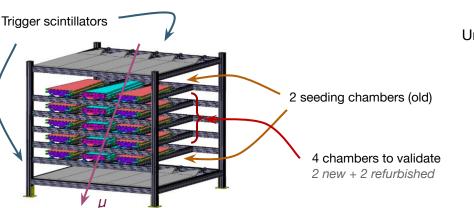
GE2/1 refurbishment plan:

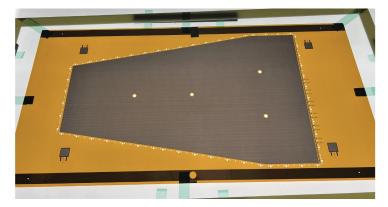
- Opening all 98 modules
- PCB refurbishment at CERN MPT workshop
- Re-assembly and QC

Estimated time to complete production: 2.6 to 3.1 years

#### **Priority shifts to ME0:**

- Stopping GE2/1 foil production at CERN and start with ME0 (2024)
- KCMS has started the ME0 foil production already
- Beginning of ME0 detector production in March 2024





First production ME0 foil at KCMS

Until ME0 components arrive, GE2/1 production continues:

• Assembled **4 GE2/1 chambers** 

2 with new modules, 2 refurbished

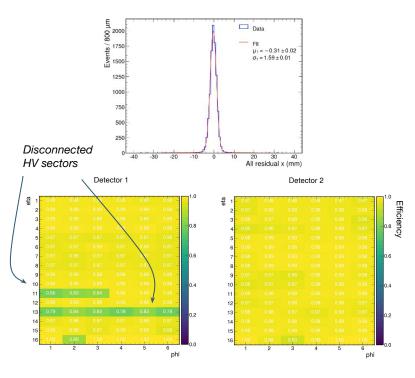
- Tested at CERN in "cosmic stand" Telescope using final electronics and services
- We will **install the two best** chambers in CMS this year 1 new + 1 refurbished

#### **Outlook on GE2/1 chamber validation**

We did a **test round** of chamber validation with cosmics for **non-refurbished** chambers: **still a few surprises** to be understood

**CMS** Preliminary Cluster charge (ADC) Sitting idle 3000 1 year 2000 1500  $\pm i\eta = 1 \pm i\eta = 2$ 1000  $\pm i\eta = 3 \pm i\eta = 4$ 500 24 Oct 2023 -400 -300 -200 -100 0 100 200 300 Average efficiency 0.868 CMS Preliminary After opening 400 400 200 Cluster charge (ADC) Propagated x (mm) Measurement on 23 Nov 2023 1000 in = 1 + in = 2Gain dips found in 4 modules 1 year after production (but seems to disappear after opening the detector and flushing)

Instead the **refurbished and new** chambers show good stability and efficiency **uniformity** 



Fist chambers almost ready for installation

-300 -200 -100

100 200

300

0

#### **In conclusion**

Long way since beginning of Phase-2 GEM production:

• **GE1/1 lessons** applied to GE2/1 production:

noise, cross-talk, readout protection, efficiency uniformity

Or learning to live with: timing...

- Initially produced almost 1 GE2/1 endcap
- PCB quality issue: rescheduling project to prioritize ME0
- Defined a GE2/1 refurbishment procedure and first chambers will be installed this year

Still training the next generation of experts...

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